

**Search Notes**

Application/Control No.

10/565,394

Examiner

Hau V. Phan

Applicant(s)/Patent under  
Reexamination

KOBAYASHI ET AL.

Art Unit

3618

**SEARCHED**

Class	Subclass	Date	Examiner
180	89.2 309	9/12/2007	HP
	296		
	219		
181	250	9/12/2007	HP
	207		
	273		
	227		
60	322	9/12/2007	HP
	299		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner